



DOCUMENT CHANGE REQUEST

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|------------|-------------|-----------------------|------------|---------------|----------------|
| DCR number | 817 | Changes required for: | General | Originator: | Steve Jeffery |
| Date: | 2014/01/24 | Date sent: | 2013/09/23 | Organisation: | ESCC Executive |
| Status: | IMPLEMENTED | | | | |

Title: Evaluation Test Programme for Discrete Non-Microwave Semiconductors

Number: 2265000 Issue: 2

Other documents affected:

Page:

9, 10, 11, 13, 14, 15, 16, 21

Paragraph:

5.2, 5.4, 5.6, 5.8.2, 6, 7.3.2, 7.3.4, 7.3.5, 7.4.2, Chart I

Original wording:

See attachment (ESCC Detail Specification 2265000 Draft 3A).

Proposed wording:

See attachment (ESCC Detail Specification 2265000 Draft 3A).

Justification:

To amend, where applicable, certain test & measurement references stated in 2265000 Issue 2: these editorial changes will make the references consistent with the ESCC format of the Generic (& Detail) Specifications.

Attachments:

2265000_draft_3a.docx, null

Modifications:

N/A

Approval signature:

Date signed:

2014-01-24